Session 12 Overview: Innovations in Low-Power and Secure IoT TECHNOLOGY DIRECTIONS SUBCOMMITTEE







event-driven wake-up IC, followed by a paper proposing reflective and MIMO antenna arrays to improve the efficiency of Wi-Fi backscattering systems. The final paper addresses key security challenges by presenting an advanced PUF solution using spectral regrowth of a power amplifier 12021 IEEE International Solid- Systems. The final paper addresses key rate Circuits Conference (ISSCC) 1978-1-28 the RF fingerprint for IoT devices.



7:00 AM

12.1 A 148nW General-Purpose Event-Driven Intelligent Wake-Up Chip for AloT Devices Using Asynchronous Spike-Based Feature Extractor and Convolutional Neural Network

Zhixuan Wang, Peking University, Beijing, China

In Paper 12.1, Peking University presents a 148nW general-purpose event-driven intelligent wake-up chip. An asynchronous spike-based feature extractor and CNN-based intelligent inference engine achieves a keyword hit rate of up to 94.1% and 99.7% abnormal ECG wake-up hit rate.



7:08 AM

12.2 Improving the Range of WiFi Backscatter Via a Passive Retro-Reflective Single-Side-Band-Modulating MIMO Array and Non-Absorbing Termination

Miao Meng, University of California San Diego, La Jolla, CA

In Paper 12.2, the University of California, San Diego introduces a 38µW IC that performs both fully reflective singleside-band (SSB) Wi-Fi backscattering for single antenna designs, and a retro-reflective SSB Wi-Fi backscattering using a MIMO antenna array, providing 4 and 15 dB improvements over prior-art, resulting in communication ranges beyond 20m.



7:16 AM

12.3 Exploring PUF-Controlled PA Spectral Regrowth for Physical-Layer Identification of IoT Nodes *Qiang Zhou, Rice University, Houston, TX*

In Paper 12.3, Rice University demonstrates a 2.4GHz PA whose spectral regrowth is used as the RF fingerprint for robust physical-layer identification. A reliable >11.5dB out-of-band leakage power variation and <1.5dB in-band variation is achieved. Sixteen unique PUF settings are measured per chip, showing a close-to-uniform distribution.